	Search Notes			
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Application/Control No.	Applicant(s)/Paten Reexamination	t under
10/632,196	PATFIELD, KEVIN	N M.
Examiner	Art Unit	
SYED ZAIDI	2616	

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370	352	5/29/2008	SZ
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	DATE	EXMR
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Inventors : PATFIELD, KEVIN M.	5/29/2008	SZ
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